Rev. 03/05/04

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

cants:

Thomas M. Mccleskey

Docket No.: S-100,631

Serial No.:

10/616,479

Examiner: Frederick J. Parker

Filed

JUL 13 2006

7/8/2003

Art Unit: 1762

For

POLYMER-ASSISTED DEPOSITION OF FILMS

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.56, 1.97, AND 1.98

Sir:

The documents listed below are identified in compliance with the duty of disclosure defined in 37 CFR 1.56. Copies are attached as appropriate.

- Chien, US Patent 5,171,735, issued December 15, 1992. 1.
- 2. Gong et al., US Patent 5,318,800, issued June 7, 1994.

CERTIFICATE OF MAILING/TRANSMISSION (37 CFR 1.8(a))

I hereby certify that this correspondence is, on the date shown below, being:

MAILING

 ☑ deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to the: Commissioner for Patents, P. O. Box 1450. Alexandria, VA 22313-1450.

Date July 11, 2006 Bruce H. Cottrell

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- 3. Sakamaki et al., US Patent 6,255,762, issued July 3, 2001.
- 4. Gallagner et al., US Patent 5,540,981, issued July 30, 1996.
- 5. Chien, US Patent 4,931,427, issued June 5, 1990.
- 6. Wu, US Patent 5,262,394, issued November 16, 1993.
- 7. Pebler et al., US Patent 4,485,094, issued November 27, 1984.
- 8. Nayfeh et al., US Patent 6,410,934, issued June 25, 2002.
- 9. Bruno et al., US Patent 5,382,452, issued January 17, 1995.
- 10. Fogelberg et al., US Patent 4,289,816, issued September 15, 1981.
- 11. Greenberg et al., US Patent 6,027,766, issued February 22, 2000.
- 12. Desaulniers, US Patent 5,441,767, issued August 15, 1995.
- 13. Haisma et al, US patent 4,617,206, issued October 14, 1986.
- 14. Li et al., US Patent 6,589,457, Issued July 8, 2003.
- 15. Lang, "Chemical Solution Routes to Single-Crystal Thin Films," Science, no. 5277, vol. 273, pp. 903-909, 1996.
- 16. Schwartz, "Chemical Solution Deposition of Perovskite Thin Films," Chem. Mater., vol. 9, no. 11, pp 2325-2340, 1997.

This Information Disclosure Statement is not to be construed as a representation that a search has been made or that additional matter material to the examination of this application does not exist. Applicant does not believe that any of these citations constitutes prior art under 35 U.S.C. 102.

It is requested that the above citations be made of record in the prosecution of this application.

Respectfully submitted,

Date: July 11, 2006

Reg. No. 30,620

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Signature of Attorney

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LC/IP, MS A187

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PTO form 1449A					Complete if Known			
INFORMATION DISCLOSURE						ation Number	10/616,479	
						Date	7/8/2003	
STATEMENT BY APPLICANT					First Named Inventor		Thomas M. Mccleskey	
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	1	US-5,171,7	'35	12/15/1992				
		US-5,318,800		06/07/1994	-			
		US-6,255,762		07/03/2001				
	1	US-5,540,9	981	07/30/1995				
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Examiner Initials	Cite No.	Foreign Patent <u>Document</u> Country Code ³ - Number ⁴ - Kind Code ⁵ (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
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I INFORMATION DISCLOSURE				Application Number	10/616,479		
STATEMENT BY APPLICANT			LICANT	Filing Date	7/8/2003		
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		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published (when known) Lang, "Chemical Solution Routes to Single-Crystal Thin Films,"	T ²
		Science, no. 5277, vol. 273, pp. 903-909, 1996.	
		Schwartz, "Chemical Solution Deposition of Perovskite Thin Films," Chem. Mater., vol. 9, no. 11, pp 2325-2340, 1997.	
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Examiner Signature		Date Considered	

¹ Applicant's unique citation designation number (optional). T² Applicant is to place a check mark here if English language Translation is attached.